

## References

- Danish, M., Ali, S., Mazhar, M., Badshah, A., Choudhary, M. I., Alt, H. G. & Kehr, G. (1995). *Polyhedron*, **14**, 3115–3123.
- Danish, M., Alt, H. G., Badshah, A., Ali, S., Mazhar, M. & Islam, N. (1995). *J. Organomet. Chem.* **486**, 51–56.
- Fan, H.-F. (1991). *SAPI91. Structure Analysis Programs with Intelligent Control*. Rigaku Corporation, Tokyo, Japan.
- Gielen, M., Buolam, M., Mahieu, B. & Tieckink, E. R. T. (1992). *Appl. Organomet. Chem.* **6**, 59–67.
- Gielen, M., Khlofli, A. E., Biesemans, M., Willem, R. & Piret, J. M. (1992). *Polyhedron*, **11**, 1861–1868.
- Johnson, C. K. (1976). *ORTEPII*. Report ORNL-5138. Oak Ridge National Laboratory, Tennessee, USA.
- Lockhart, T. P., Calabrese, J. C. & Davidson, F. (1987). *Organometallics*, **6**, 2479–2483.
- Molecular Structure Corporation (1988). *MSC/AFCS Diffractometer Control Software*. MSC, 3200 Research Forest Drive, The Woodlands, TX 77381, USA.
- Molecular Structure Corporation. (1994). *TEXSAN. Single Crystal Structure Analysis Software*. MSC, 3200 Research Forest Drive, The Woodlands, TX 77381, USA.
- North, A. C. T., Phillips, D. C. & Mathews, F. S. (1968). *Acta Cryst. A* **24**, 351–359.
- Piret, J. M., Buolam, M., Willem, R. & Gielen, M. (1993). *Main Group Met. Chem.* **16**, 392–434.
- Sandhu, G. K., Hundal, R. & Tieckink, E. R. T. (1991). *J. Organomet. Chem.* **412**, 31–38.
- Sandhu, G. K., Sharma, N. & Tieckink, E. R. T. (1989). *J. Organomet. Chem.* **371**, C1–C3.
- Sheldrick, G. M. (1993). *SHELXL93. Program for the Refinement of Crystal Structures*. University of Göttingen, Germany.
- Tieckink, E. R. T. (1991). *J. Organomet. Chem.* **409**, 323–327.
- Vatsa, C., Jain, V. K., Das, T. K. & Tieckink, E. R. T. (1991). *J. Organomet. Chem.* **410**, 135–142.

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## Two Heteroleptic Cobalt(III) Cyclopentadienyl/Dithiolene Complexes

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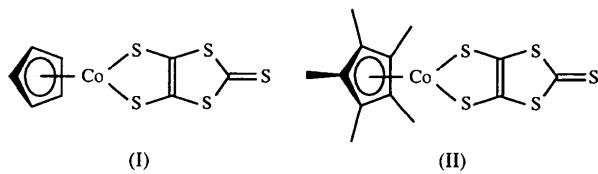
### Abstract

The crystal structure determinations of ( $\eta^5$ -cyclopentadienyl)(4,5-dimercapto-1,3-dithiole-2-thionato)cobalt(III),  $[\text{Co}(\text{C}_5\text{H}_5)(\text{C}_3\text{S}_5)]$ , and (4,5-dimercapto-1,3-dithiole-2-thionato)( $\eta^5$ -pentamethylcyclopentadienyl)cobalt(III),  $[\text{Co}(\text{C}_{10}\text{H}_{15})(\text{C}_3\text{S}_5)]$ , show that  $\text{Cp}^*$  substitution does not significantly modify the geometric features of these complexes, which are characterized by a perpendicular arrangement of the planar  $\text{Cp}$  or  $\text{Cp}^*$  and  $(\text{CoS}_2\text{C}_2)$  moieties.

## Comment

In the course of our work on electroactive materials built from heteroleptic cyclopentadienyl/dithiolene complexes with Ti, Nb and Mo (Fourmigué & Coulon, 1994; Fourmigué, Lenoir, Coulon, Guyon & Amaudrut, 1995; Guyon, Fourmigué, Audebert & Amaudrut, 1995; Guyon, Lenoir, Fourmigué, Larsen & Amaudrut, 1990), we have been interested in the corresponding Co complexes of general formula  $\text{CpCo}(\text{dithiolene})$ , where  $\text{Cp}$  is the cyclopentadienyl ligand. The structures of such  $\text{Co}^{III}$  complexes with various dithiolenes have been reported, e.g.  $\text{S}_2\text{C}_2(\text{CN})_2$  (Churchill & Fennessey, 1968),  $\text{S}_2\text{C}_2(\text{CF}_3)_2$  (Baird & White, 1966),  $\text{S}_2\text{C}_6\text{H}_4$  (Miller, Brill, Rheingold & Fultz, 1983); complexes with nitrogen-containing dithiolenes have also been reported (Werner, Xiaolan & Nurnberg, 1992; Armstrong *et al.*, 1993). More recently, sulfur-rich dithiolene ligands such as  $\text{dmit}^{2-}$  or  $\text{dddt}^{2-}$  (where  $\text{dmit}^{2-}$  is 4,5-dimercapto-1,3-dithiole-2-thionate and  $\text{dddt}^{2-}$  is 5,6-dihydro-1,4-dithiine-2,3-dithiolate) have been used (Ushijima *et al.*, 1990, 1991) and the electrochemical properties of the complexes investigated. These latter ligands have been shown to be particularly versatile in homoleptic paramagnetic complexes as, for example, in  $\text{Ni}(\text{dmit})_2^-$ , since they promote a solid-state organization with strong intermolecular  $\text{S}\cdots\text{S}$  interactions, a prerequisite for the setting of collective electronic properties such as conductivity, superconductivity and magnetism (Canadell, Ravy, Pouget & Brossard, 1990).

In this paper, the crystal structures of  $\text{CpCo}(\text{dmit})$ , (I), and  $\text{Cp}^*\text{Co}(\text{dmit})$ , (II), are reported. The geometry of the cyclopentadienyl complex, (I), is compared with that of previously reported complexes as well as with the  $\text{Cp}^*$  analogue, (II), for which no crystal structure with any dithiolene ligand has been reported previously.



In both compounds, the  $\text{Co}(\text{S}_2\text{C}_2)$  moiety is nearly planar and perpendicular to the  $\text{Cp}$  [88.4 (2) $^\circ$ ] and the  $\text{Cp}^*$  [87.8 (2) $^\circ$ ] moieties. The dimensions of the  $[(\eta^5\text{C}_5\text{H}_5)\text{Co}(\text{S}_2\text{C}_2)]$  moiety in (I) are similar to those of each of the five structurally characterized molecules of this type. With the  $\text{Cp}^*$  ligand, a slight elongation of the  $\text{Co}—\text{S}$  bonds was observed, which might be attributable to the more electron-rich character of the  $\text{Cp}^*$  ligand when compared with the  $\text{Cp}$  ligand.

In the solid state, short  $\text{S}\cdots\text{S}$  contacts are identified in (I) [ $\text{S}4\cdots\text{S}1^i$  3.608 (3),  $\text{S}2\cdots\text{S}1^i$  3.655 (3) and  $\text{S}4\cdots\text{S}3^i$  3.733 (3) Å; symmetry code: (i)  $x - 1, y, z$ ], thus linking the parallel  $\text{dmit}$  moieties of neighbouring molecules obtained by translation along the  $a$  axis. These short

contacts in (I) are attributable to the combined effects of van der Waals (Ellern *et al.*, 1994) and  $\pi$ - $\pi$  interactions (Hunter & Sanders, 1990), while in (II), the larger Cp\* ligand prevents such a compact packing and S···S contacts appear to be larger than the sum of the van der Waals radii (3.7 Å) [S2···S3<sup>ii</sup> 3.807 (5), S4···S1<sup>ii</sup> 3.869 (5) Å; symmetry code: (ii)  $-x + \frac{3}{2}, y + \frac{1}{2}, -z + \frac{3}{2}$ ].

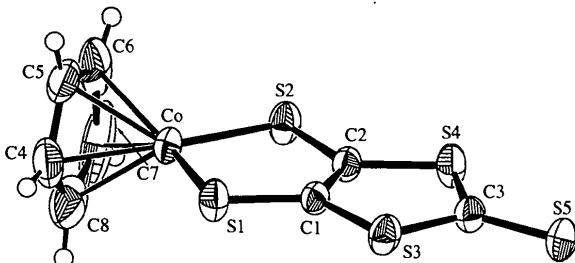


Fig. 1. Molecular structure of (I) with displacement ellipsoids drawn at the 50% probability level.

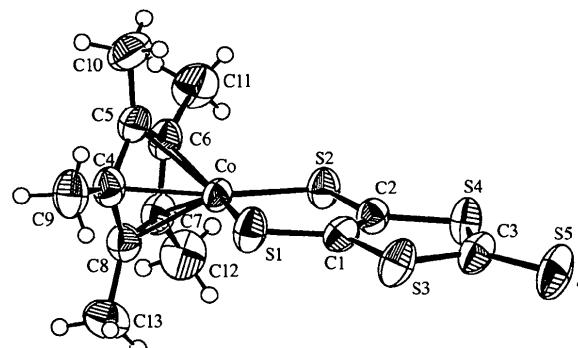


Fig. 2. Molecular structure of (II) with displacement ellipsoids drawn at the 50% probability level.

## Experimental

Compounds (I) and (II) were prepared as described previously (Ushijima *et al.*, 1990). Single crystals of (I) and (II) were obtained by recrystallization from toluene and ethyl acetate, respectively.

### Compound (I)

#### Crystal data



$M_r = 320.35$

Monoclinic

$P2_1/n$

$a = 5.9564 (8)$  Å

$b = 7.8830 (3)$  Å

$c = 23.2930 (3)$  Å

$\beta = 97.180 (10)^\circ$

$V = 1085.1 (5)$  Å<sup>3</sup>

$Z = 4$

$D_x = 1.961$  Mg m<sup>-3</sup>

$D_m$  not measured

Mo K $\alpha$  radiation

$\lambda = 0.71073$  Å

Cell parameters from 25 reflections

$\theta = 8.3\text{--}15.5^\circ$

$\mu = 2.494$  mm<sup>-1</sup>

$T = 293 (2)$  K

Plate

$0.180 \times 0.150 \times 0.045$  mm

Black

#### Data collection

Enraf–Nonius CAD-4 diffractometer

$\omega$ - $2\theta$  scans

Absorption correction:

$\psi$  scan (SHELXTL/PC; Sheldrick, 1995)

$T_{\min} = 0.722, T_{\max} = 0.894$

2338 measured reflections

2126 independent reflections

1484 reflections with

$I > 2\sigma(I)$

$R_{\text{int}} = 0.187$

$\theta_{\max} = 25.97^\circ$

$h = 0 \rightarrow 7$

$k = 0 \rightarrow 9$

$l = -28 \rightarrow 28$

3 standard reflections

frequency: 60 min

intensity decay: none

#### Refinement

Refinement on  $F^2$

$R(F) = 0.032$

$wR(F^2) = 0.073$

$S = 1.106$

2126 reflections

127 parameters

H-atom parameters constrained; see below

$$w = 1/[\sigma^2(F_o^2) + (0.0396P)^2 + 0.852P]$$

where  $P = (F_o^2 + 2F_c^2)/3$

$(\Delta/\sigma)_{\max} < 0.001$

$\Delta\rho_{\max} = 0.511$  e Å<sup>-3</sup>

$\Delta\rho_{\min} = -0.476$  e Å<sup>-3</sup>

Extinction correction: none

Scattering factors from

International Tables for Crystallography (Vol. C)

### Compound (II)

#### Crystal data



$M_r = 390.525$

Monoclinic

$P2_1/n$

$a = 12.140 (2)$  Å

$b = 11.488 (2)$  Å

$c = 12.698 (3)$  Å

$\beta = 110.91 (2)^\circ$

$V = 1654.3 (6)$  Å<sup>3</sup>

$Z = 4$

$D_x = 1.568$  Mg m<sup>-3</sup>

$D_m$  not measured

Mo K $\alpha$  radiation

$\lambda = 0.71073$  Å

Cell parameters from 2000 reflections

$\theta = 2\text{--}24^\circ$

$\mu = 1.65$  mm<sup>-1</sup>

$T = 293$  K

Plate

$0.39 \times 0.28 \times 0.03$  mm

Black

#### Data collection

Stoe IPDS diffractometer

Rotation scans,  $\Delta\varphi = 3^\circ$

Absorption correction:

numerical (FACEIT; Stoe & Cie, 1995)

$T_{\min} = 0.591, T_{\max} = 0.940$

10 261 measured reflections

2641 independent reflections

1725 reflections with

$F > 3\sigma(F)$

$R_{\text{int}} = 0.076$

$\theta_{\max} = 24.27^\circ$

$h = -13 \rightarrow 13$

$k = -13 \rightarrow 13$

$l = -14 \rightarrow 14$

#### Refinement

Refinement on  $F$

$R = 0.05$

$wR = 0.055$

$S = 1.193$

1725 reflections

172 parameters

H-atom parameters constrained; see below

$(\Delta/\sigma)_{\max} = 0.004$

$\Delta\rho_{\max} = 0.809$  e Å<sup>-3</sup>

$\Delta\rho_{\min} = -1.45$  e Å<sup>-3</sup>

Extinction correction: none

Scattering factors from

International Tables for Crystallography (Vol. C)

Table 1. Selected geometric parameters ( $\text{\AA}$ ,  $^\circ$ ) for (I) and (II)

	(I)	(II)
Co—S1	2.1233 (11)	2.138 (2)
Co—S2	2.1266 (11)	2.135 (2)
S1—C1	1.705 (3)	1.713 (6)
S2—C2	1.702 (4)	1.725 (7)
S3—C1	1.733 (3)	1.741 (7)
S4—C2	1.738 (4)	1.739 (6)
S3—C3	1.714 (4)	1.719 (6)
S4—C3	1.728 (4)	1.725 (8)
S5—C3	1.661 (4)	1.657 (7)
C1—C2	1.377 (5)	1.352 (9)
Mean Co—C†	2.028 (12)	2.050 (7)
S1—Co—S2	93.20 (4)	93.65 (7)
C1—S1—Co1	103.14 (13)	102.3 (2)
C2—S2—Co2	103.30 (12)	102.3 (2)

† Estimated errors on averaged Co—C distances are calculated as  $\sigma = [\sum(d_i - d_{\text{mean}})^2/(n-1)]^{1/2}$ ,  $n=5$ .

Data for (II) were collected with an area detector (Stoe IPDS) with a crystal-to-plate distance of 80 mm ( $\theta_{\text{max}} = 24.27^\circ$ ), an exposure time of 5 min per plate, with  $\varphi$  varying from 0 to  $200^\circ$  by increments  $\Delta\varphi = 3^\circ$ ; the duration of measurement was 10 h. With respect to the  $\psi$ -scan absorption correction for (I), discrepancies between the resulting  $T_{\text{max}}/T_{\text{min}}$  values and those expected from the  $\mu$  value and crystal size might be attributable to the very thin shape of the crystal, which makes an accurate determination of the smallest crystal dimension difficult. H atoms were introduced at calculated positions, included in structure-factor calculations and not refined (riding model). In the final electron-density map of (II), the strongest negative density peak was found to be  $-1.45 \text{ e } \text{\AA}^{-3}$  in the vicinity (1  $\text{\AA}$ ) of the Co atom. Two C atoms (C6 and C7) of the Cp ring in (I) exhibit strongly anisotropic displacement parameters ( $U_3/U_1 = 12$ ), but attempts to introduce a disorder model for the Cp ring were unsuccessful.

Data collection: CAD-4 EXPRESS (Enraf-Nonius, 1994) for (I); EXPOSE (Stoe & Cie, 1995) for (II). Cell refinement: CAD-4 EXPRESS for (I); SELECT (Stoe & Cie, 1995) for (II). Data reduction: XCAD-4 (Harms, 1993) for (I); INTEGRATE (Stoe & Cie, 1995) for (II). Program(s) used to solve structures: SHELXS86 (Sheldrick, 1990) for (I); Xtal3.2 (Hall, Flack & Stewart, 1992) for (II). Program(s) used to refine structures: SHELXL93 (Sheldrick, 1993) for (I); Xtal3.2 for (II). For both compounds, molecular graphics: ORTEPII (Johnson, 1976). Software used to prepare material for publication: SHELXL93 for (I); Xtal3.2 for (II).

Supplementary data for this paper are available from the IUCr electronic archives (Reference: AB1475). Services for accessing these data are described at the back of the journal.

## References

- Armstrong, E. M., Austerberry, M. S., Beddoes, R. L., Hellwell, M., Joule, J. A. & Garner, C. D. (1993). *Acta Cryst. C49*, 1764–1766.
- Baird, H. W. & White, B. M. (1966). *J. Am. Chem. Soc. 88*, 4744–4745.
- Canadell, E., Ravy, S., Pouget, J.-P. & Brossard, L. (1990). *Solid State Commun. 75*, 633–638.
- Churchill, M. R. & Fennessey, J. P. (1968). *Inorg. Chem. 7*, 1123–1129.
- Ellern, A., Bernstein, J., Becker, J. Y., Zamir, S., Shalal, L. & Cohen, S. (1994). *Chem. Mater. 6*, 1378–1385.
- Enraf-Nonius (1994). CAD-4 EXPRESS. Version 5.1/1.2. Enraf-Nonius, Delft, The Netherlands.
- Fourmigué, M. & Coulon, C. (1994). *Adv. Mater. 6*, 948–952.
- Fourmigué, M., Lenoir, C., Coulon, C., Guyon, F. & Amaudrut, J. (1995). *Inorg. Chem. 34*, 4979–4985.
- Guyon, F., Fourmigué, M., Audebert, P. & Amaudrut, J. (1995). *Inorg. Chim. Acta, 239*, 117–124.
- Guyon, F., Lenoir, C., Fourmigué, M., Larsen, J. & Amaudrut, J. (1990). *Bull. Soc. Chim. Fr. 131*, 217–226.
- Hall, S. R., Flack, H. D. & Stewart, J. M. (1992). Editors. *Xtal3.2 Reference Manual*. Universities of Western Australia, Australia, Geneva, Switzerland, and Maryland, USA.
- Harms, K. (1993). XCAD-4. *Program for the Reduction of CAD-4 Diffractometer Data*. University of Marburg, Germany.
- Hunter, C. A. & Sanders, J. K. M. (1990). *J. Am. Chem. Soc. 112*, 5525–5534.
- Johnson, C. K. (1976). ORTEPII. Report ORNL-5138. Oak Ridge National Laboratory, Tennessee, USA.
- Miller, E. J., Brill, T. B., Rheingold, A. L. & Fultz, W. (1983). *J. Am. Chem. Soc. 105*, 7580–7584.
- Sheldrick, G. M. (1990). *Acta Cryst. A46*, 467–473.
- Sheldrick, G. M. (1993). SHELXL93. *Program for the Refinement of Crystal Structures*. University of Göttingen, Germany.
- Sheldrick, G. M. (1995). SHELXTL/PC. Version 5.04. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.
- Stoe & Cie (1995). IPDS. *Imaging Plate Diffractometer System*. Stoe & Cie, Darmstadt, Germany.
- Ushijima, H., Sudoh, S., Kajitani, M., Shimizu, K., Akiyama, T. & Sugimori, A. (1990). *Inorg. Chim. Acta, 175*, 11–12.
- Ushijima, H., Sudoh, S., Kajitani, M., Shimizu, K., Akiyama, T. & Sugimori, A. (1991). *Appl. Organomet. Chem. 5*, 221–228.
- Werner, H., Xiaolan, L. & Nürnberg, O. (1992). *Organometallics, 11*, 432–436.
- Acta Cryst. (1997). C53, 1215–1218
- Bis(2,2'-bipyridine-N,N')(tricyanomethanido-N)copper(II) Tricyanomethanide**
- IVAN POTOČNÁK,<sup>a</sup> MICHAL DUNAJ-JURČO,<sup>a</sup> DUŠAN MIKOĽA<sup>a</sup> AND LOTHAR JÄGER<sup>b</sup>
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## Abstract

The crystal structure of  $[\text{Cu}\{\text{C}(\text{CN})_3\}(\text{C}_{10}\text{H}_8\text{N}_2)_2]\text{[C}(\text{CN})_3]$  is formed by discrete  $[\text{Cu}(\text{bipy})_2\{\text{C}(\text{CN})_3\}]^+$  cations and  $[\text{C}(\text{CN})_3]^-$  anions (bipy is 2,2'-bipyridine). The coordination polyhedron of  $\text{Cu}^{II}$  is a distorted trigonal bipyramidal with a  $\{\text{CuN}_5\}$  chromophore.